



## Notice of References Cited

Application/Control No.

10/049,511

Examiner

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Applicant(s)/Patent Under
Reexamination
DELFOURNE ET AL.

Art Unit
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## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
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## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Matsumato et al. (Tetrahedron Letters 41 (2000) 1667-1670, issue of March 4, 2000).
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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